

Form PTO 1449  
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New Application

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Hiroyoshi TANIMOTO, et al.

FILING DATE

Herewith

GROUP

11011 U.S. PTO  
10/001977

12/05/01

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

PEP	AW	Robert H. TU, et al., "BERKELEY RELIABILITY TOOLS-BERT", IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 12, No. 10, October 1993, pgs. 1524 - 1534.
PEP	AX	Chenming HU, et al., "HOT-ELECTRON-INDUCED MOSFET DEGRADATION-MODEL, MONITOR, AND IMPROVEMENT", IEEE Transactions on Electron Devices, Vol. ED-32, No. 2, February 1985, pgs. 375 - 385.
	AY	
	AZ	

Examiner

Date Considered

2-10-03

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.